



## SHENZHEN TAILONGYUAN TECHNOLOGY CO., LTD

# CE EMC REPORT

Prepared For :	SHENZHEN TAILONGYUAN TECHNOLOGY CO., LTD  Room 426, 4th Floor, Western Tea City, West 1 Times Shopping Plaza, Sha Enterprise Community, Xinqiao Street, Baoan District, Shenzhen City, Guangdong Province
Product Name:	PORTABLE POWER SUPPLY
Trade Name:	TAILONYU
Model :	T101
Prepared By :	Shenzhen BST Technology Co., Ltd.  Building No.23-24, Zhiheng Industrial Park, Guankouer Road, Nantou, Nanshan District, Shenzhen, Guangdong, China
Test Date:	Dec. 25-26, 2018
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## TEST REPORT DECLARATION

Applicant	:	SHENZHEN TAILONGYUAN TECHNOLOGY CO., LTD
Address	:	Room 426, 4th Floor, Western Tea City, West 1 Times Shopping Plaza, Sha Enterprise Community, Xinqiao Street, Baoan District, Shenzhen City, Guangdong Province
EUT Description	:	PORTABLE POWER SUPPLY
Model Number	:	T101

Test Standards:

- EN 61000-6-3:2007/A1:2011/AC:2012
- EN61000-3-2:2014
- EN61000-3-3:2013
- EN61000-6-1:2007

The EUT described above is tested by BST Technology Co., Ltd. EMC Laboratory to determine the maximum emissions from the EUT and ensure the EUT to be compliance with the immunity requirements of the EUT. BST Technology Co., Ltd. EMC Laboratory is assumed full responsibility for the accuracy of the test results. Also, this report shows that the EUT technically complies with the 2014/30/EU directive and its amendment requirements.

The test report is valid for above tested sample only and shall not be reproduced in part without written approval of the laboratory.

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Approved & Authorized Signer :

*Mike Mo*

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## 1. TEST RESULTS SUMMARY

Table 1 Test Results Summary

Test Items	Test Results
Radiated Emission	PASS
Conducted Disturbance	PASS
Harmonic Current	PASS
Voltage Fluctuation and Flicker	PASS
Electrostatic Discharge Immunity	PASS
Radiated Electromagnetic Fields Immunity	PASS
Electric Fast Transient Burst Immunity	PASS
Surge Immunity	PASS
Injected currents susceptibility test	PASS
Voltage dips and interruptions Immunity	PASS